

ABSTRACT OF THE DISCLOSURE

67 A test pattern which is delivered from an LSI tester simulator and a
corresponding test cycle number are stored in a first memory (26) while device
output data which is formed by CAD data and a corresponding test time are
67 stored in a second memory (27). The test pattern in the first memory and the
device output data in the corresponding second memory are extracted by a
67 comparing and synchronizing unit (28) and are then input to the LSI tester
27 simulator (10). In the LSI tester simulator, the device output data is compared
against expected values. If the entire device output data are in coincidence
with the expected values, this test pattern is determined to be acceptable. In
addition, a verification is made to see whether or not a strobe pulse which
defines the determination timing for the comparison between the device
output data and the expected values has occurred for all the states in the
device output data.